



Inspect the invisible in one go.

The new level of simplicity

ZEISS METROTOM 1

With the easy-to-use CT technology of the ZEISS Metrotom 1, anyone can efficiently perform complex measurement and inspection tasks with just one scan. Measure and inspect hidden defects and internal structures that cannot be detected with tactile or optical measuring systems.



Easy handling

Installation is quick and only little training is needed for safe handling of ZEISS METROTOM 1



Precise measurements

Perform nominal/actual comparisons, dimensional checks, and wall thickness analyses with confidence



Small footprint

With dimensions of 1750 (W) \times 1820 (H) \times 870 (D) mm, the CT system fits into any metrology lab



Fast return on invest

Acquisition costs as well as cost of ownership are minimal with the low-maintenance system

Applications

Whether medium or small sized parts, plastic or light metal – with ZEISS METROTOM 1, you can inspect a variety of components such as connectors, plastic caps, aluminum parts and more.







Specifications

X-ray source	160 kV
X-ray detector	2.5 k
Measuring volume	165 x 140 mm
Voxel size	66 µm

Metrology specification	SD < 5 μm
Dimensions	1750 (W) x 1820 (H) x 870 (D) mm
Weight	2100 kg
Software	GOM Volume Inspect (included)

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